

Gate-Tunable Resonance State and Screening Effects for Proton-Like Atomic Charge in Graphene

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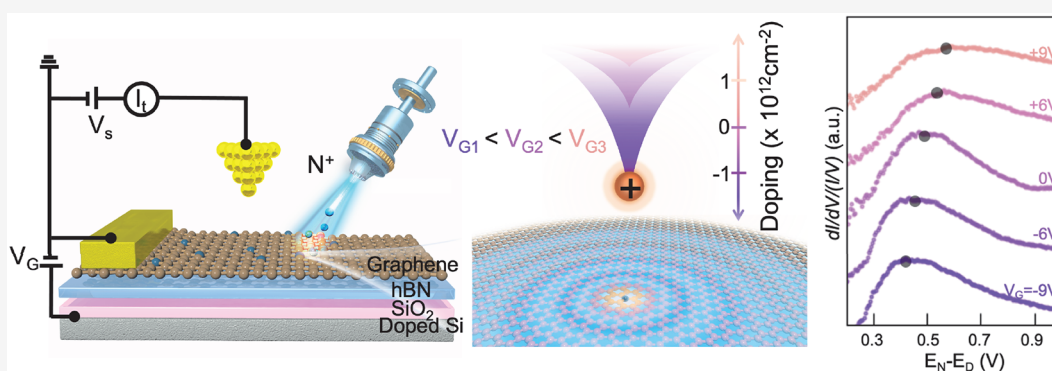
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ABSTRACT: The ability to create a robust and well-defined artificial atomic charge in graphene and understand its carrier-dependent electronic properties represents an important goal toward the development of graphene-based quantum devices. Herein, we devise a new pathway toward the atomically precise embodiment of point charges into a graphene lattice by posterior (N) ion implantation into a back-gated graphene device. The N dopant behaves as an in-plane proton-like charge manifested by formation of the characteristic resonance state in the conduction band. Scanning tunneling spectroscopy measurements at varied charge carrier densities reveal a giant energetic renormalization of the resonance state up to 220 meV with respect to the Dirac point, accompanied by the observation of gate-tunable long-range screening effects close to individual N dopants. Joint density functional theory and tight-binding calculations with modified perturbation potential corroborate experimental findings and highlight the short-range character of N-induced perturbation.

KEYWORDS: graphene, nitrogen doping, impurity, back-gated device, ion implantation

The relativistic-like electronic dispersion in graphene offers a rich platform for studying exotic quantum electrodynamics phenomena in a condensed-matter setup as well as for developing novel electronics and quantum optics.^{1,2} This photon-like band structure also makes graphene electrons much less amenable to electrostatic confinement compared to conventional materials. The ability to create a robust atomically precise Coulomb charge in graphene and understand its carrier-dependent electronic properties at the nanoscale represents an important goal toward the development of graphene-based quantum devices. To date, the Coulomb charge problem in graphene has been addressed via scanning tunneling microscopy (STM)-assisted studies of highly charged transition-metal adatoms,^{3–7} one-dimensional molecular arrays on graphene,^{8,9} and creating a vacancy in the back-gated graphene device.¹⁰ Nevertheless, the extent of the potential produced by “out-of-plane” charge centers above graphene is expected to be very different from the “in-plane”

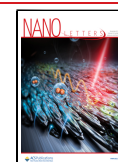
charges hosted in graphene,^{11–13} while in-plane carbon vacancies tend to undergo structural reconstructions manifested by emergence of characteristic spin-polarized states.¹⁴ This distinction hinges on a question: Is it possible to controllably fabricate in-plane point positive charges in a graphene lattice in a *true* two-dimensional (2D) limit and further probe the associated response of the Dirac Fermions as a function of carrier density?

The ideal scenario of an in-plane Coulomb charge center assumes a point charge residing in the graphene plane without imposing any lattice deformations. The most viable way to

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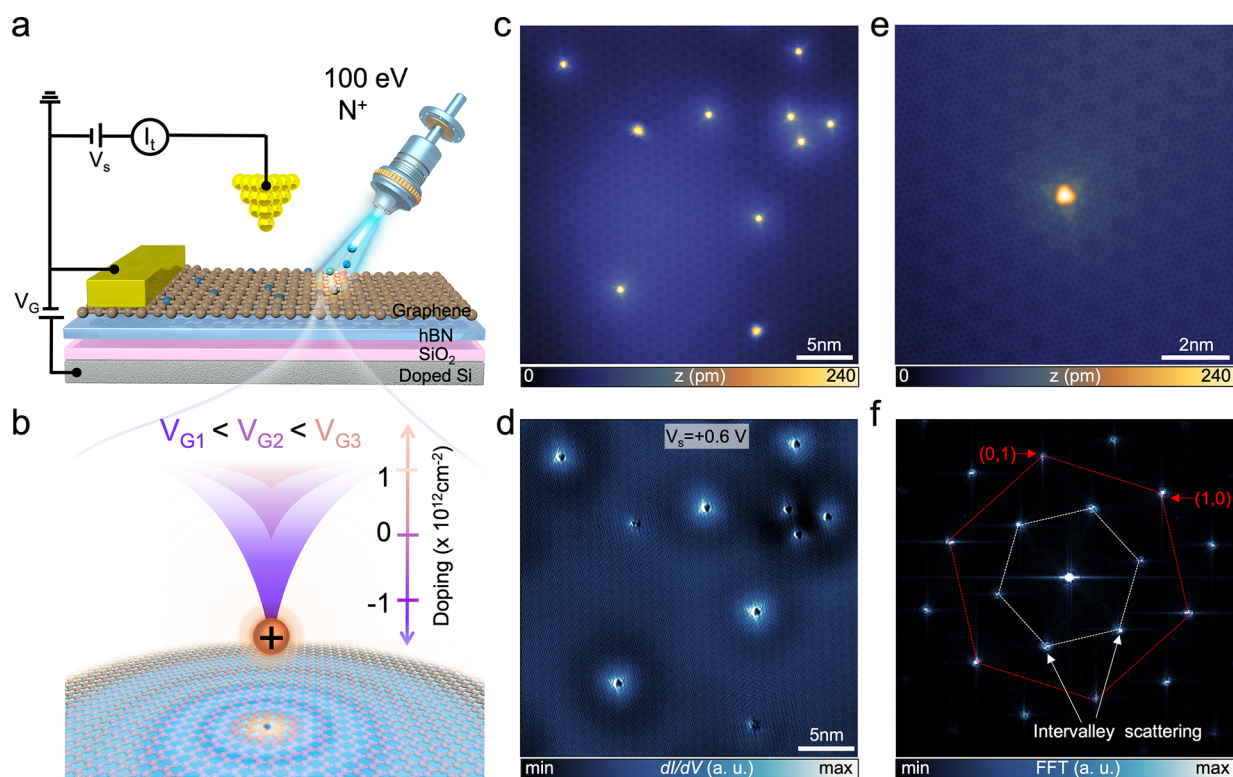


Figure 1. Creating substitutional nitrogen dopants in back-gated G/BN. (a) Schematics showing the route toward incorporation of N dopant into back-gated G/BN using low-energy (+100 eV) N⁺ ion implantation. (b) Schematic illustration of a tunable proton-induced potential via gating. (c) Large-scale STM image reveals the presence of individual substitutional N atoms. (d) dI/dV map acquired at V_s = +0.6 V over the same surface area as STM image in panel (c). (e) Enlarged image of individual N dopant. (f) Fast Fourier transformation of the STM image of individual N dopant.

create such a scenario is to utilize nitrogen (N) substitution into graphene. The similarity of atomic radii of N and C, accompanied by the ability of N to adopt sp² hybridization, allows for its facile incorporation into the graphene lattice. In addition, due to the proximity of N and C in the periodic table and one more proton of N nuclei than C, sp²-like N substitution in graphene is essentially equivalent to injecting a single proton into one of the lattice sites of pristine graphene. Previously both atom-resolved imaging^{15–24} and sample-averaged spectroscopic techniques^{25–29} have been extensively deployed to probe structural and electronic properties of N impurities in graphene. Nevertheless, all these studies utilized heavily doped graphene layers with altered intrinsic electronic structure due to the presence of the underlying substrates, including silicon carbide,^{15,22,30} Cu(111),^{20,23} or another graphene layer,²⁴ that obstructed deciphering of both short- and long-range electronic effects associated with N atoms in pristine single-layer graphene at varied charge carrier densities. Therefore, back-gated graphene-boron nitride (G/BN) devices harboring atomically smooth and charge-homogeneous interfaces³¹ may provide an ideal platform to probe unique electronic behavior around N impurities in a tunable and poorly screened environment. On the other hand, the viable routes of high-yield posterior sp²-like N incorporation directly into back-gated graphene device have been hitherto missing.

Here, we have devised a well-controlled N⁺ ion implantation routine allowing for a high-yield sp²-like incorporation of individual N atoms into the graphene lattice (Figure 1a,b) in a back-gated G/BN device. Individual N dopants behave as in-plane artificial protons, manifested by the emergence of a

broad resonance state (E_N) above the Dirac point together with long-range Friedel oscillations in the vicinity of N dopants. Using gate-tunable dI/dV measurements, we demonstrate that the strength of the proton's potential can be effectively modified via tuning charge carrier density in graphene, leading to a giant gate-tunable energetic shift of the N-induced resonance state (E_N) with respect to the Dirac point. Such a phenomenon not only has not been demonstrated to date but also is in stark contrast to gate-tunable behavior of other reported atomically precise impurities in graphene with electronic resonances pinned to the Dirac point. Density functional theory (DFT) and effective tight-binding (TB) theory calculations with modified on-site perturbation potential and hopping constant corroborate the emergence of the new resonance state and its associated gate-tunable correlation effects.

We first fabricated the back-gated device consisting of chemical vapor deposition (CVD)-grown monolayer graphene on top of a hexagonal boron-nitride flake (G/BN) placed onto a SiO₂ substrate, as shown in Figure 1a (also see Supporting Information). Gate voltage (V_G), applied between the electrostatically grounded graphene sheet and the doped Si wafer, enables the tunability of the carrier density in graphene (Figure 1b).

Our route toward the N atoms embodiment in back-gated G/BN (Figure 1a) relies on its posterior bombardment using low-energy (+100 eV) N⁺ ions in ultrahigh vacuum conditions, as illustrated in Figure 1a (see Methods for further details). This process results in a robust sp²-like incorporation of individual N atoms into graphene. The representative STM

images reveal that the surface of the G/BN after N⁺ implantation is decorated with abundant triangular-shaped features attributed to the individual N dopants (Figure 1c). It is noted that the apparent height of the in-plane N sites strongly depends on applied bias voltage (see Figure S3). A higher apparent height observed in a larger positive sample bias is attributed to their enhanced empty density of electronic states as discussed in detail further below.

High-resolution STM imaging (Figure 1e) and dI/dV mapping (Figure 1d) of the single N dopant in graphene demonstrate the characteristic $\sqrt{3} \times \sqrt{3}$ pattern associated with the intervalley electron scattering processes, which has also been revealed in the vicinity of atomic-scale defects, including hydrogen adatoms³² and carbon vacancies.^{10,33} Characteristic spots attributed to electron backscattering processes between K and K' valleys are also evident in the Fourier-transformed STM image (Figure 1f).

Next, we probed the electronic properties of the N dopants via the acquisition of the site-specific dI/dV point spectra in the nearly neutral doping regime (i.e., $V_G = 0$ V), which reveal several prominent features (Figure 2a,b). These include (i) a gap-like feature (~ 130 meV) centered at the Fermi level (E_F) attributed to the phonon-assisted inelastic tunneling³⁴ and (ii) an electron–hole asymmetry with reduced (increased) spectral weight of the hole (electron) dI/dV branch, decaying with distance from the N site (Figure 3a). This indicates a net positive charge of the N dopant^{19,35} as expected from a partially screened proton in the graphene lattice. (iii) The dI/dV spectra acquired over the N site (Figure 2a) and in its proximity reveal a broad resonance state (denoted as E_N) centered at ~ 590 meV above E_F , as further illustrated by the normalized dI/dV spectra (see Supporting Information). The 2D contour map of the dI/dV spectra (Figure 2b) reveals the spatial extent of the N-induced resonance state gradually decaying with distance from the N site and fading beyond ~ 1.7 nm.

In addition, bias-dependent dI/dV maps reveal characteristic concentric rings in the vicinity of the N dopant that are attributed to the Friedel oscillations (FOs). The dI/dV maps acquired at negative sample biases (Figure 2c) display an attenuated dI/dV intensity in direct proximity to the N site surrounded by brighter FO rings. In contrast, dI/dV maps acquired at positive sample biases (Figure 2d) feature a reversed contrast with an enhanced dI/dV signal close to the N site, surrounded by FO rings with a lower dI/dV intensity. It is noteworthy that the diameter of the FO rings scales inversely with the bias voltage as revealed also by dI/dV line scans normalized with respect to the tunneling conductance value (i.e., $dI/dV/(I/V)$), acquired at different V_s values shown in Supporting Information. For instance, the dI/dV line scans acquired at $V_s = -0.6$, -0.5 , and -0.4 V feature FO rings with a diameter of 4.16, 5.76, and 7.30 nm, respectively. The FO diameter is also found to be tunable by charge-carrier density as evidenced by dI/dV line scans acquired at varied V_G (see Supporting Information).

We then explored carrier-dependent electronic properties of the N dopant by acquiring the dI/dV spectra at various V_G values ranging from $V_G = -9$ V (p-doped regime) to $V_G = +9$ V (n-doped regime). Prior to this, gate-dependent dI/dV spectra acquired over nearby graphene (>10 nm away) exhibit a characteristic energy shift of Dirac point (“dip-feature” marked by red dots) in Figure 4b, whereby the carrier concentration at $V_G = +9$ V is estimated to be $n_e \approx 1.8 \times 10^{12}$

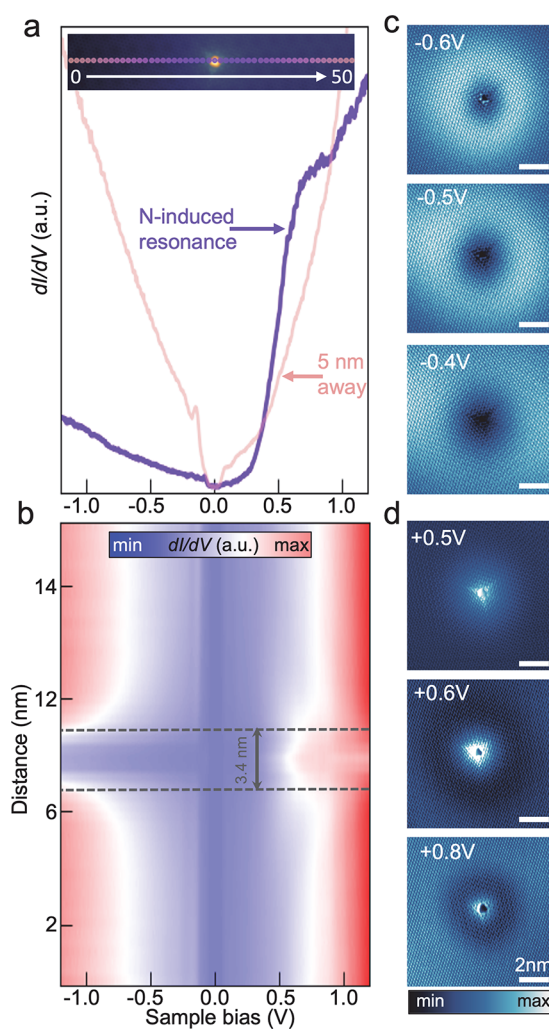


Figure 2. Characterization of individual N dopants. (a) dI/dV spectra acquired over N-site and pristine graphene. (b) 2D color-coded contour plot constructed from the set of point dI/dV spectra acquired along the line traversing single N dopant indicated in the inset STM image in panel (a). (c, d) dI/dV maps acquired at negative (c) and positive (d) bias voltages indicated in top-left corners. Length of each scale bar is 2 nm. The dI/dV spectra were acquired at tunneling set point $V_s = +1.2$ V, $I = 2$ nA.

cm^{-2} using a standard capacitor model^{36,37} (see Methods). Note that the charge neutrality point of graphene is close to $V_G = 0$ (see Supporting Information). In contrast, the normalized point dI/dV spectra (see Supporting Information) acquired over the N site reveal a slightly V_G -dependent energetic shift of E_N , from 497 mV (at $V_G = -9$ V) to 464 mV (at $V_G = 0$ V) (Figure 4a). Further, gating graphene into the n-doped regime ($V_G = +9$ V) leads to a notable broadening of E_N and an attenuation of its spectral weight.

The site-specific dI/dV measurements discussed above enable the determination of the V_G -dependent energetic position of the E_N with respect to the Dirac point (Figure 4c). With account of the phonon-assisted inelastic tunneling process³⁴ (details in Methods), it is evident that a gradual variation of the back-gate voltage V_G from -9 to $+9$ V leads to a monotonic shift of E_N from ~ 415 to ~ 635 mV relative to the Dirac point (black dots in Figure 4c). Such a giant carrier density-dependent energetic renormalization of the N-induced resonance state with respect to the Dirac point (i.e., ~ 220

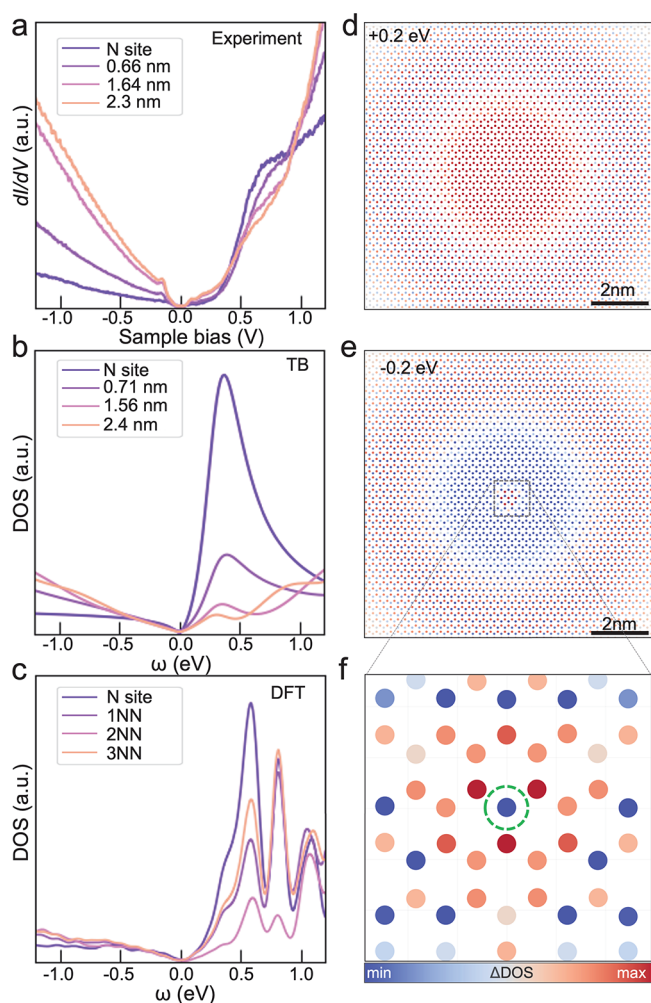


Figure 3. Electronic structures of individual N dopants. (a) dI/dV spectra acquired over an N site and its vicinity (tunneling set point $V_s = +1.2$ V, $I = 2$ nA). (b) Site-specific DOS spectra acquired over an N site and its vicinity using TB model for perturbation potential (Δ) values of: $\Delta_0 = -7$ eV, $\Delta_1 = -0.7$ eV, and $\delta t = 0.5$ eV. (c) DFT-calculated DOS of the N site and its first (1NN), second (2NN), and third (3NN) nearest C neighbors in a 10×10 supercell. (b, c) ω is the energy measured from the Dirac point. (d, e) Real space spectral function maps calculated at energies of $+0.2$ (d) and -0.2 (e) eV using TB formalism. The colors represent the local deviation of the spectral function from the value of pristine graphene (ΔDOS). (f) Enlarged image of area marked by square in panel (e). Dashed green circle marks the position of N site.

meV) sets N dopants apart from other previously studied impurities residing in a back-gated graphene. Specifically, it has been shown that the electronic resonance states associated with hydrogen adatoms,^{18,38} single carbon vacancies, and¹⁰ cobalt clusters⁴ are energetically pinned to the Dirac point and thus exhibit a rigid shift with the Dirac point as a function of V_G . The nonrigid shift of molecular frontier orbitals with respect to V_G has been recently attributed to many-electron interactions and gate-tunable graphene's polarization effects.³⁹ In the most general sense, the peak in the spectral function can be viewed as a consequence of the attractive potential created by the extra proton in the nitrogen nucleus. The electronic density in the material and the associated screening effects can be controlled by gating. Modifying the screening alters the

potential produced by the proton, consequently shifting the peak in the spectral function.

We first carried out DFT calculations to understand both local structural and electronic properties of a single N dopant in graphene. Specifically, DFT-calculated projected density of states (DOS) for the p_z orbitals of the N dopant, along with its first, second, and third nearest C neighbors, reveals a peak centered at ~ 500 meV above E_F (Figure 3c), consistent with the experimental spectrum. The presence of multiple peaks above the Fermi energy in the DFT spectra arises from an artifact of N-impurity interactions caused by the periodic boundary conditions⁴⁰ imposed by the finite supercell size. In the limit of an infinitely large cell, as in the present TB formulation, these peaks would vanish. We would like to point out that the salient features of the DFT spectra, namely, the location of the N-induced peak and its weakening away from a N site, are qualitatively in agreement with our experimental observations presented in Figure 3a. Importantly, our DFT calculations also indicate that the presence of N in graphene renders a rather negligible lattice distortion, with almost identical lengths of C–N (1.41 Å) and C–C (1.42 Å) bonds. Moreover, graphene's lattice remains flat, retaining its sp^2 hybridization, preventing any spin-flip processes, and preserving the separation of graphene π and σ bands. Consequently, N substitution allows for the formation of the desired in-plane Coulomb center while maintaining the sp^2 integrity of graphene.

To describe the effects of the N dopant, we employ tight-binding calculations with the formalism described in ref 41 using a Julia language⁴² package.⁴³ Since the TB approach with nearest-neighbor hopping works well for graphene, and since the p_z orbitals of nitrogen are smaller than those of carbon (see Supporting Information), it should be possible to only change the on-site energy of the dopant and its neighbors (by adding energies Δ_0 and Δ_1 , respectively) and adjust the hopping parameters (δt) to describe the N-induced broad resonance state. Indeed, we find that such a perturbation, with $\Delta_0 = -7$ eV, $\Delta_1 = -0.7$ eV, and $\delta t = 0.5$ eV, shown in Figure 3b, gives a good agreement with the ab initio results (Figure 3c), reinforcing the short-range nature of the N-induced perturbation. In addition, real-space spectral function maps calculated using the TB formalism reproduce experimental dI/dV maps by revealing both the characteristic triangular shape near to N (Figure 3f) and the surrounding FO concentric rings, arising from the intravalley scattering⁴⁴ (Figure 3d,e). We note that earlier work⁴⁰ presents different TB parameters. We would like to emphasize that our values agree with the DFT profiles better and that both parametrizations capture the essential features and do not lead to different qualitative results.

As discussed above, substituting a C with an N can be viewed as injecting a proton into the system. Consequently, one might expect the emergence of long-range effects arising from the Coulomb potential produced by this proton instead of the short-range perturbation suggested by the DFT and TB calculations. To reconcile these two pictures, one can start with the proton-generated $1/r$ attractive potential, which gives rise to bound states with energies below the lowest kinetic energy that particles can have. In the case of graphene, the relevant system of particles corresponds to the π -band electrons. The DFT calculations confirm the existence of a deep energy bound state below the π band (Figure S8 and S9). Naturally, this state will become occupied, and the electron will screen

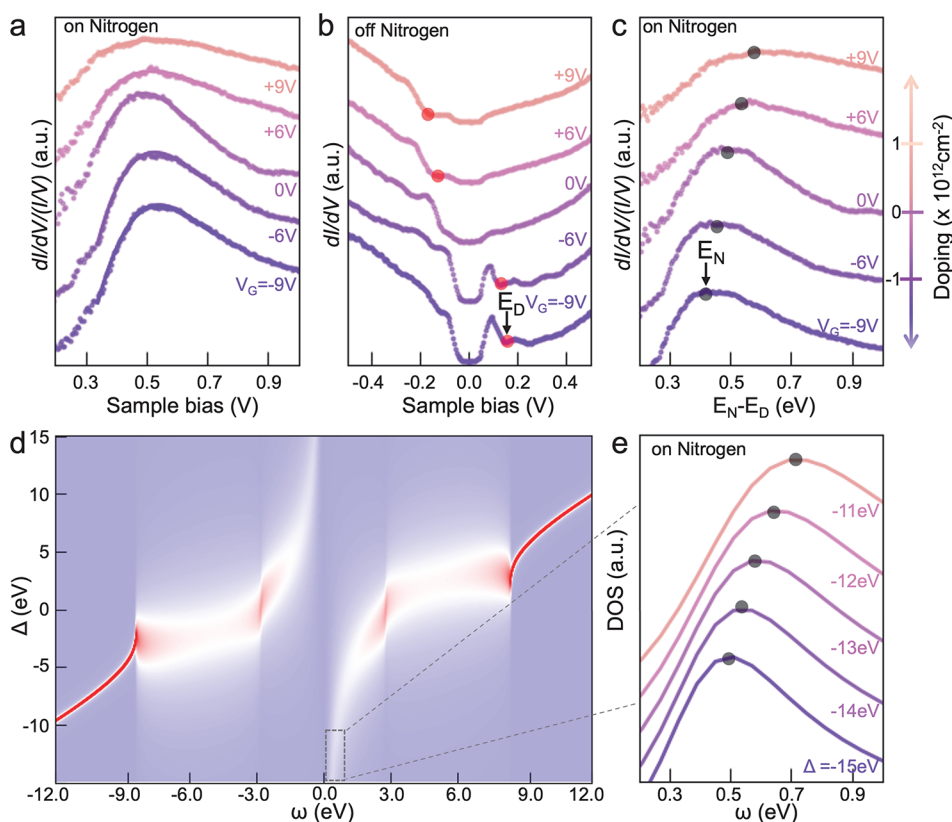


Figure 4. Gate-tunable electronic properties of N dopant. (a) Normalized $dI/dV/(I/V)$ spectra acquired over N site at various V_G . (b) dI/dV spectra acquired over pristine graphene area at various V_G . Red dots mark positions of Dirac point (E_D). (c) Energetic positions of N-induced resonance state (E_N) with respect to E_D extracted from site-specific dI/dV spectra acquired at various V_G , with account of the phonon-assisted inelastic tunneling process. Black dots mark the maxima of E_N . (d) Color-coded TB spectral plot with $\omega = 0$ corresponding to the Dirac point. (e) TB spectra extracted for monotonously varied values of the perturbation potential (Δ). The dI/dV spectra were acquired at the tunneling set point of $V_s = +1.2$ V, $I = 2$ nA.

the proton, sharply diminishing the extent of the Coulomb potential. Additionally, the surrounding atoms also screen the positive charge, further reducing the potential's range.

One last question that remains is the gate-dependent renormalization of the N-induced resonance state (E_N) with respect to the Dirac point. A variation of carrier density in graphene is expected to further modulate the screened potential of the added proton, equivalent to tuning the on-site energy of the dopant and its neighbors, and the hopping parameter between them, in the TB formalism.

More specifically, sweeping the back-gate voltage from $V_G = -9$ V to $V_G = +9$ V, corresponding to an electron density of $n_e \approx 1.8 \times 10^{12} \text{ cm}^{-2}$ in the system, provides additional screening to the already-screened proton, effectively weakening its ability to lower the potential energy of other electrons. In our toy model, this is equivalent to making on-site energies less negative and pushing the resonance state to higher energies (Figure 4d). While the entire band structure shifts to lower energy due to gating, the net effect is manifested as the V_G -dependent E_N resonance state lagging behind the Dirac point (Figure 4c). As the simplest illustration, we only include the on-site energy modification Δ for the nitrogen dopant and plot the dopant's spectral function for a range of Δ values in Figure 4d. The respective plots for the (next-)nearest carbon neighbor are shown in Supporting Information. We observe that, as the on-site potential is varied, the energy difference between the resonance in the conduction band and the Dirac point changes (Figure 4e), as seen in the experiment. In addition, one can

expect the formation of a bound state below the band minimum for sufficiently large Δ values, as seen in Figure 4d.

In summary, we have devised a new route toward a controllable sp^2 -like incorporation of N atoms into back-gated Gr/BN. The N dopant, seamlessly embedded into the graphene lattice, behaves as an artificial proton with dominant short-ranged potential perturbation, leading to the formation of a broad resonance state above the Dirac point. The strength of the proton's potential can be effectively modified via tuning charge carrier density in graphene, leading to a giant gate-tunable energetic renormalization of the resonance state up to 220 meV with respect to the Dirac point, which is in a stark contrast to gate-tunable response of other atomically precise impurities in graphene reported to date. It can be envisaged that synergy of the uncovered atomically precise N^+ implantation technique, with a judiciously designed device patterning strategy, may enable facile fabrication of nanoscale linear^{45,46} or circular^{47–49} p–n junctions in graphene for developing novel electronics and quantum optics. In addition, controllable N substitution developed here may allow to trace the evolution of the gate-tunable bands associated with midgap states in Bernal-stacked bilayer graphene²⁴ and to address the Coulomb problem in the magic-angle twisted graphene bilayers with strong correlation effects.⁵⁰

■ ASSOCIATED CONTENT

SI Supporting Information

The Supporting Information is available free of charge at <https://pubs.acs.org/doi/10.1021/acs.nanolett.2c02235>.

Experimental methods, including details of G/BN device fabrication and theoretical calculations; additional experimental dI/dV measurements, theoretical DOS and TB data (PDF)

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Author Contributions

M.T., A.R., and J.Lu. conceived the project. M.T. performed experiments related to ion implantation of Gr/BN, STM/STS measurements, and data analysis. K.N., H.B., D.D., Z.W.Y., and A.R. performed DFT and TB calculations. P.L., J.Li, and Z.C. fabricated a back-gated Gr/BN device under the guidance of K.P.L., J.W., H.-Z.T., and M.F.C.; K.W. and T.T. grew hBN crystals for the device. H.F. and Z.Q. assisted in STM experimental procedures. The manuscript was written by M.T., A.R., and J.Lu. with contributions from all coauthors.

Notes

The authors declare no competing financial interest.

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This paper was published ASAP on October 10, 2022 with a typo in the caption of Figure S7 in the Supporting Information file. The corrected version was reposted on October 19, 2022.